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Monitoring the surface quality of silver plasmon waveguides with nonlinear photoemission electron microscopy and in-situ ion sputtering

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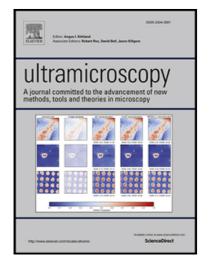
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## Highlights

- Nonlinear photoemission electron microscopy is used to image surface plasmon polariton modes in silver stripe waveguides
- Characterisation of modes complicated by surface roughness which leads to emission hot spots and high scattering losses
- In-situ low energy argon ion sputtering can improve mode contrast whilst reducing edge and hotspot emission

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